ON Semiconductor

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Field Stop Trench IGBT 650 V, 40 A

FGHL40T65MQDT

Field stop 4th generation mid speed IGBT technology copacked with full rated current diode.

Features

- Maximum Junction Temperature: $T_J = 175^{\circ}C$
- Positive Temperature Co-efficient for Easy Parallel Operating
- High Current Capability
- Low Saturation Voltage: $V_{CE(Sat)} = 1.45 \text{ V (Typ.)}$ @ $I_C = 40 \text{ A}$
- 100% of the Parts are Tested for I_{LM} (Note 2)
- Smooth and Optimized Switching
- Tight Parameter Distribution
- RoHS Compliant

Typical Applications

- Solar Inverter
- UPS, ESS
- PFC, Converters

MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Collector to Emitter Voltage		650	V
Gate to Emitter Voltage Transient Gate to Emitter Voltage		±20 ±30	٧
Collector Current (Note 1) @ $T_C = 25^{\circ}C$ @ $T_C = 100^{\circ}C$	I _C	60 40	Α
Pulsed Collector Current (Note 2)	I _{LM}	160	Α
Pulsed Collector Current (Note 3)	I _{CM}	160	Α
Diode Forward Current (Note 1) @ T_{C} = 25°C @ T_{C} = 100°C	IF	60 40	Α
Pulsed Diode Maximum Forward Current	I _{FM}	160	Α
	P _D	238 119	W
Operating Junction and Storage Temperature Range	T _J , T _{STG}	-55 to +175	°C
Maximum Lead Temp. for Soldering Purposes (1/8" from case for 5 s)	T _L	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

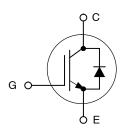
- 1. Value limit by bond wire
- 2. V_{CC} = 400 V, V_{GE} = 15 V, I_{C} = 160 A, Inductive Load, 100% tested
- 3. Repetitive rating: pulse width limited by max. junction temperature



ON Semiconductor®

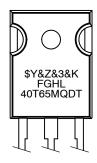
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40 A, 650 V V_{CESat} = 1.45 V





MARKING DIAGRAM



\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = 3-Digit Date Code

&K = 2-Digit Lot Traceability Code FGHL40T65MQDT = Specific Device Code

ORDERING INFORMATION

Device	Package	Shipping
FGHL40T65MQDT	TO-247-3L	30 Units / Tube

THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal Resistance Junction-to-case, for IGBT	$R_{ heta JC}$	0.63	°C/W
Thermal Resistance Junction-to-case, for Diode	$R_{ heta JC}$	0.91	°C/W
Thermal Resistance Junction-to-ambient	$R_{ heta JA}$	40	°C/W

ELECTRICAL CHARACTERISTICS (T_{.I} = 25°C unless otherwise noted)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS				•		
Collector to Emitter Breakdown Voltage	$V_{GE} = 0 V$, $I_C = 1 mA$	BV _{CES}	650	-	-	V
Temperature Coefficient of Breakdown Voltage	V _{GE} = 0 V, I _C = 1 mA	$\frac{\Delta BV_{CES}}{\Delta T_{J}}$	-	0.6	-	V/°C
Collector to Emitter Cut-off Current	V _{GE} = 0 V, V _{CE} = 650 V	I _{CES}	_	-	250	μА
Gate Leakage Current	V _{GE} = 20 V, V _{CE} = 0 V	I _{GES}	-	-	±400	nA
ON CHARACTERISTICS						_
Gate to Emitter Threshold Voltage	$V_{GE} = V_{CE}$, $I_C = 40 \text{ mA}$	V _{GE(th)}	3.0	4.5	6.0	V
Collector to Emitter Saturation Voltage	V _{GE} = 15 V, I _C = 40 A, T _J = 25°C V _{GE} = 15 V, I _C = 40 A, T _J = 175°C	V _{CE(sat)}	- -	1.45 1.65	1.8 -	V
DYNAMIC CHARACTERISTICS		•	-	-		
Input Capacitance	V _{CE} = 30 V,	C _{ies}	_	2680	_	pF
Output Capacitance	V _{GE} = 0 V, f = 1 MHz	C _{oes}	_	80	_	
Reverse Transfer Capacitance	1 1	C _{res}	_	9	_	
Gate Charge Total	V _{CE} = 400 V, I _C = 40 A, V _{GE} = 15 V	Q_g	_	80	_	nC
Gate to Emitter Charge		Q_ge	-	16	-	1
Gate to Collector Charge		Q_{gc}	_	19	_	1
SWITCHING CHARACTERISTICS, INDUC	TIVE LOAD					
Turn-on Delay Time	T _J = 25°C,	t _{d(on)}	_	16	_	ns
Rise Time	$V_{CC} = 400 \text{ V},$ $I_{C} = 20 \text{ A},$	t _r	_	10	_	
Turn-off Delay Time	$R_G = 6 \Omega$, $V_{GE} = 15 V$	t _{d(off)}	_	82	_	
Fall Time	- GL 12 1	t _f	_	51	_	1
Turn-on Switching Loss		E _{on}	_	0.35	_	mJ
Turn-off Switching Loss		E _{off}	_	0.25	_	1
Total Switching Loss		E _{ts}	_	0.60	-	
Turn-on Delay Time	$T_J = 25^{\circ}C$, $V_{CC} = 400 \text{ V}$, $I_C = 40 \text{ A}$,	t _{d(on)}	_	18	_	ns
Rise Time		t _r	_	22	_	1
Turn-off Delay Time	$R_G = 6 \Omega$, $V_{GE} = 15 V$	t _{d(off)}	-	75	-	1
Fall Time	• GE - 10 V	t _f	_	38	_	1
Turn-on Switching Loss		E _{on}	-	0.88	-	mJ
Turn-off Switching Loss		E _{off}	-	0.49	-	1
Total Switching Loss	1	E _{ts}	_	1.36	_	1

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
SWITCHING CHARACTERISTICS, IND	UCTIVE LOAD	•		•		•
Turn-on delay time	T _J = 175°C,	t _{d(on)}	-	16	_	ns
Rise time	$V_{CC} = 400 \text{ V},$ $I_{C} = 20 \text{ A},$	t _r	-	11	_	
Turn-off delay time	$R_G = 6 \Omega$, $V_{GE} = 15 V$	t _{d(off)}	-	93	_	
Fall time	- GE	t _f	-	88	-	
Turn-on switching loss		E _{on}	-	0.64	-	mJ
Turn-off switching loss		E _{off}	-	0.49	_	
Total switching loss		E _{ts}	-	1.13	-	
Turn-on delay time	T _J = 175°C,	t _{d(on)}	-	16	-	ns
Rise time	$V_{CC} = 400 \text{ V},$ $I_{C} = 40 \text{ A},$	t _r	-	26	-	
Turn-off delay time	$R_G = 6 \Omega$, $V_{GE} = 15 V$	t _{d(off)}	-	85	-	
Fall time		t _f	-	75	-	
Turn-on switching loss		E _{on}	-	1.31	-	mJ
Turn-off switching loss		E _{off}	_	0.90	_	1
Total switching loss		E _{ts}	-	2.21	-	
DIODE CHARACTERISTICS	•	-			•	
Diode Forward Voltage	I _F = 40 A, T _J = 25°C	V _F	-	1.7	2.15	V
	I _F = 40 A, T _J = 175°C		-	1.65	-	
DIODE SWITCHING CHARACTERISTIC	CS, INDUCTIVE LOAD	-			•	
Reverse Recovery Energy	$T_J = 25^{\circ}C$, $V_{CE} = 400 \text{ V}$, $I_F = 20 \text{ A}$,	E _{rec}	-	54	_	μЈ
Diode Reverse Recovery Time	di _F /dt = 1000 A/μs	T _{rr}	-	42	_	ns
Diode Reverse Recovery Charge		Q _{rr}	-	329	-	nC
Diode Reverse Recovery Current		I _{rr}	-	15	-	Α
Reverse Recovery Energy	T _J = 25°C, V _{CE} = 400 V, I _F = 40 A,	E _{rec}	-	121	-	μJ
Diode Reverse Recovery Time	di _F /dt = 1000 A/μs	T _{rr}	-	86	-	ns
Diode Reverse Recovery Charge		Q _{rr}	-	665	-	nC
Diode Reverse Recovery Current		I _{rr}	-	15	-	Α
Reverse Recovery Energy	$T_J = 175^{\circ}C$, $V_{CE} = 400 \text{ V}$, $I_F = 20 \text{ A}$,	E _{rec}	-	360	-	μJ
Diode Reverse Recovery Time	di _F /dt = 1000 A/μs	T _{rr}	-	104	-	ns
Diode Reverse Recovery Charge	1	Q _{rr}	-	1379	-	nC
Diode Reverse Recovery Current		I _{rr}	-	27	-	Α
Reverse Recovery Energy	T _J = 175°C, V _{CE} = 400 V, I _F = 40 A,	E _{rec}	-	519	-	μJ
Diode Reverse Recovery Time	- di _F /dt = 1000 A/μs	T _{rr}	-	141	-	ns
Diode Reverse Recovery Charge		Q _{rr}	-	1877	_	nC
Diode Reverse Recovery Current	\neg	I _{rr}	_	26	_	Α

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS

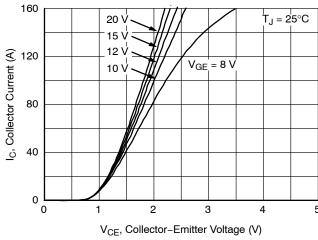


Figure 1. Typical Output Characteristics (T_J = 25°C)

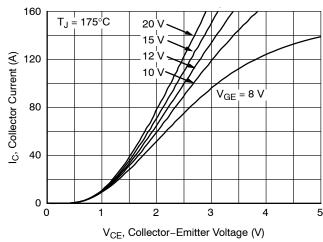


Figure 2. Typical Output Characteristics ($T_J = 175^{\circ}C$)

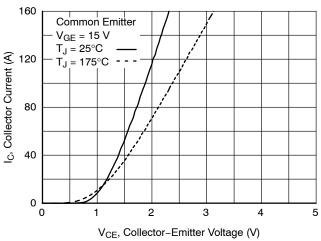


Figure 3. Typical Saturation Voltage Characteristics

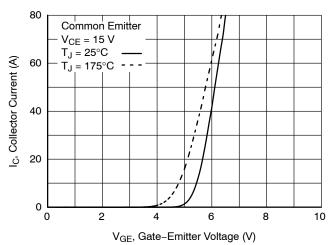


Figure 4. Typical Transfer Characteristics

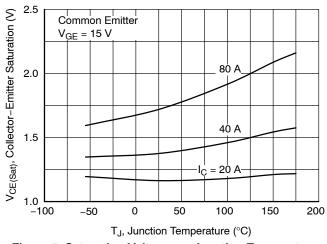


Figure 5. Saturation Voltage vs. Junction Temperature

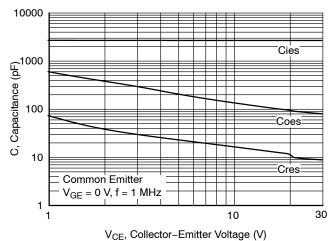


Figure 6. Capacitance Characteristics

TYPICAL CHARACTERISTICS (continued)

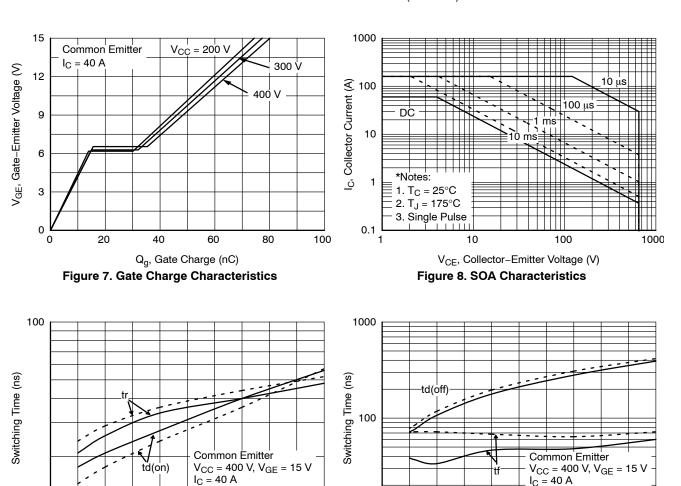


Figure 9. Turn-on Characteristics vs. Gate Resistance

 R_q , Gate Resistance (Ω)

20

10

10

 $T_J = 25^{\circ}C$

30

 $T_{J}^{-} = 175^{\circ}C$ - - -

40

Figure 10. Turn-off Characteristics vs. Gate Resistance

 R_q , Gate Resistance (Ω)

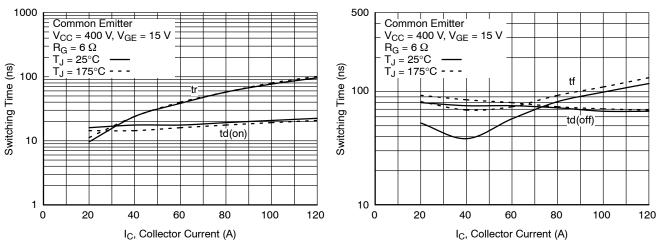
20

 $I_{C} = 40 \text{ A}$

 $\tilde{T_J} = 25^{\circ}C$

 $T_{J}^{-} = 175^{\circ}C^{-} - -$

50



10

50

10

Figure 11. Turn-on Characteristics vs. Collector Current Figure 12. Turn-off Characteristics vs. Collector Current

TYPICAL CHARACTERISTICS (continued)

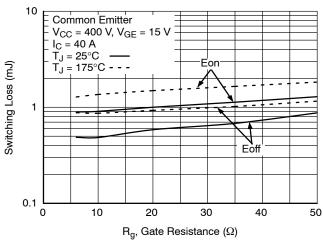


Figure 13. Switching Loss vs. Gate Resistance

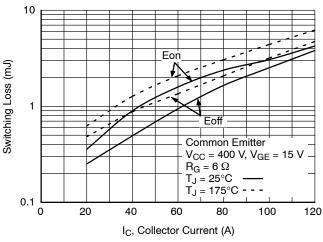


Figure 14. Switching Loss vs. Collector Current

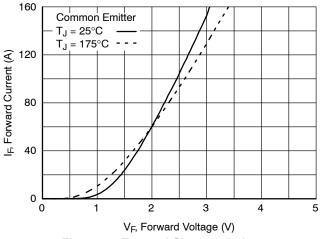


Figure 15. Forward Characteristics

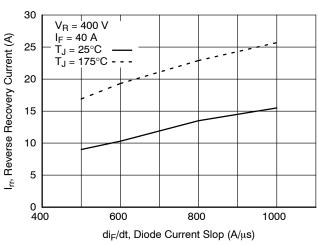


Figure 16. Reverse Recovery Current

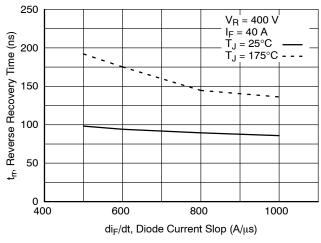


Figure 17. Reverse Recovery Time

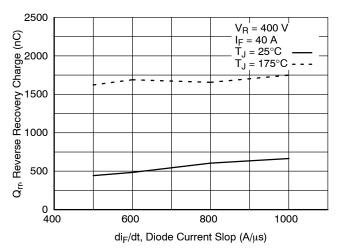


Figure 18. Stored Charge

TYPICAL CHARACTERISTICS (continued)

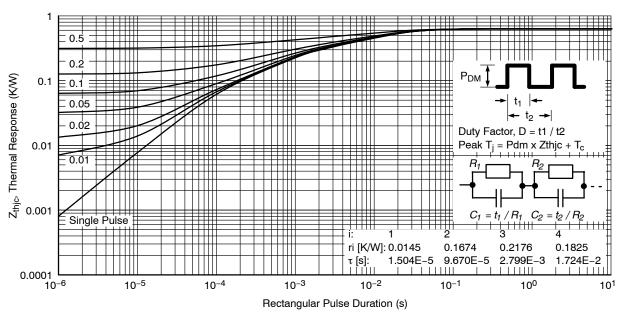


Figure 19. Transient Thermal Impedance of IGBT

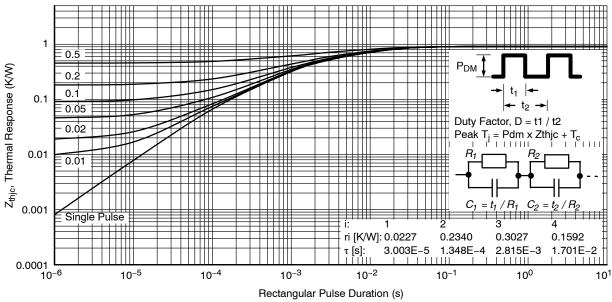
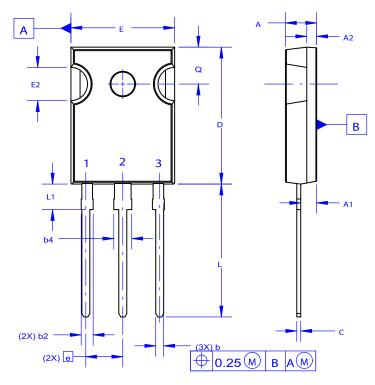


Figure 20. Transient Thermal Impedance of Diode

PACKAGE DIMENSIONS

TO-247-3LD CASE 340CX **ISSUE A**

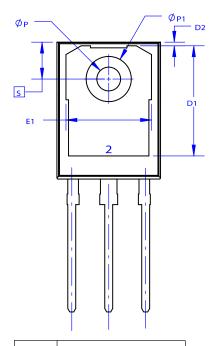


NOTES: UNLESS OTHERWISE SPECIFIED.

- A. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.

 B. ALL DIMENSIONS ARE IN MILLIMETERS.

- C. DRAWING CONFORMS TO ASME Y14.5 2009.
 D. DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED BY L1.
- E. LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY L1.



DIM	MILLIMETERS			
DIM	MIN	NOM	MAX	
Α	4.58	4.70	4.82	
A 1	2.20	2.40	2.60	
A2	1.40	1.50	1.60	
D	20.32	20.57	20.82	
Е	15.37	15.62	15.87	
E2	4.96	5.08	5.20	
е	2	5.56	~	
L	19.75	20.00	20.25	
L1	3.69	3.81	3.93	
ØΡ	3.51	3.58	3.65	
Q	5.34	5.46	5.58	
S	5.34	5.46	5.58	
b	1.17	1.26	1.35	
b2	1.53	1.65	1.77	
b4	2.42	2.54	2.66	
С	0.51	0.61	0.71	
D1	13.08	~	~	
D2	0.51	0.93	1.35	
E1	12.81	~	~	
Ø P1	6.60	6.80	7.00	

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